

# Ewelina Gacka

## Lista Publikacji

1. Gacka, E., Kunicki, P., Sikora, A., Bogdanowicz, R., Ficek, M., Gotszalk, T., Rangelow, I. W., & Kwoka, K. (2022). Focused ion beam-based microfabrication of boron-doped diamond single-crystal tip cantilevers for electrical and mechanical scanning probe microscopy. *Measurement*, 188, 110373. <https://doi.org/10.1016/j.measurement.2021.110373>;
2. Gacka, E., Kunicki, P., Łysik, P., Gajewski, K., Ciechanowicz, P., Pucicki, D., Majchrzak, D., Gotszalk, T., Piasecki, T., Busani, T., Rangelow, I. W., & Hommel, D. (2023). Novel type of whisker-tip cantilever based on GaN microrods for atomic force microscopy. *Ultramicroscopy*, 248, 113713. <https://doi.org/10.1016/j.ultramic.2023.113713>;
3. Pruchnik, B., Orłowska, K., Świadkowski, B., Gacka, E., Sierakowski, A., Janus, P., & Gotszalk, T. (2023). Microcantilever-based current balance for precise measurement of the photon force. *Scientific Reports*, 13(1), 466. <https://doi.org/10.1038/s41598-022-27369-3>;
4. Ficek, M., Głowacki, M. J., Gajewski, K., Kunicki, P., Gacka, E., Sycz, K., Mrózek, M., Wojciechowski, A. M., Gotszalk, T. P., Gawlik, W., & Bogdanowicz, R. (2021). Integration of Fluorescent, NV-Rich Nanodiamond Particles with AFM Cantilevers by Focused Ion Beam for Hybrid Optical and Micromechanical Devices. *Coatings*, 11(11), 1332. <https://doi.org/10.3390/coatings11111332>;
5. Gacka, E., Pruchnik, B., Kwoka, K., Kunicki P., Piasecki, T., Rangelow, I.W., & Gotszalk, T. (2023). Field emitters integrated with operational microelectromechanical systems – fabrication and measurements using scanning electron microscope/focused ion beam [Conference presentation]. European Focused Ion Beam Network Conference, Zurich, Switzerland.